

Electron Beam Diagnostics

Report of Contributions

Contribution ID: 1

Type: **not specified**

Beam Loss Monitors

Monday 23 November 2020 10:00 (5 minutes)

Scintillator & PMT as BL-Detector & LIBERA-BLM-Electronics

Presenter: BOBB, Lorraine (Diamond Light Source)

Session Classification: DLS-2 Electron Beam Diagnostics

Contribution ID: 2

Type: **not specified**

Streak Camera

Monday 23 November 2020 10:05 (5 minutes)

Bunch Length Diagnostics

Presenter: BOBB, Lorraine (Diamond Light Source)

Session Classification: DLS-2 Electron Beam Diagnostics

Contribution ID: 3

Type: **not specified**

Current Monitors - DCCT & ICT

Monday 23 November 2020 10:10 (10 minutes)

Presenter: MORGAN, Alun (Diamond light Source)

Session Classification: DLS-2 Electron Beam Diagnostics

Contribution ID: 4

Type: **not specified**

Filling Patern & Bunch Purity Monitors

Monday 23 November 2020 10:20 (5 minutes)

X-ray and visible light TCSPC systems

Presenter: BOBB, Lorraine (Diamond Light Source)

Session Classification: DLS-2 Electron Beam Diagnostics

Contribution ID: 5

Type: **not specified**

Profile & Emittance Monitors

Monday 23 November 2020 10:25 (30 minutes)

X-ray pinholes

YAG / OTR screens

high resolution monitor: pi-polarization / x-ray interferometer

Presenter: BOBB, Lorraine (Diamond Light Source)

Session Classification: DLS-2 Electron Beam Diagnostics

Contribution ID: 6

Type: **not specified**

Visible Light Extraction & SR Monitors

Monday 23 November 2020 10:55 (15 minutes)

Presenter: BOBB, Lorraine (Diamond Light Source)

Session Classification: DLS-2 Electron Beam Diagnostics

Contribution ID: 7

Type: **not specified**

SLS 2.0 BTR Diagnostics

Monday 23 November 2020 11:30 (10 minutes)

diagnostics layout for new SLS 2.0 booster-to-ring transfer line

Presenter: OZKAN LOCH, Cigdem (Paul Scherrer Institut)

Session Classification: SLS 2.0 Electron Beam Diagnostics

Contribution ID: 8

Type: **not specified**

SLS 2.0 Current, Filling Pattern and Bunch Length Monitors

Monday 23 November 2020 11:40 (10 minutes)

Presenter: OZKAN LOCH, Cigdem (Paul Scherrer Institut)

Session Classification: SLS 2.0 Electron Beam Diagnostics

Contribution ID: 9

Type: **not specified**

SLS 2.0 Beam Loss Monitoring

Monday 23 November 2020 11:50 (10 minutes)

Presenter: OZKAN LOCH, Cigdem (Paul Scherrer Institut)

Session Classification: SLS 2.0 Electron Beam Diagnostics

Contribution ID: **10**

Type: **not specified**

SLS 2.0 Emittance Monitoring by Beam Size Measurement

Monday 23 November 2020 12:00 (30 minutes)

Presenter: OZKAN LOCH, Cigdem (Paul Scherrer Institut)

Session Classification: SLS 2.0 Electron Beam Diagnostics